## **Model 1500 Specifications**

#### **Automatic Functions**

Auto Prealignment: Capture Window: Site by Site Alignment:

Placement:

Overlay Alignment: Target Capture Window:

Auto Focus:

Focus Gauge: Auto wafer level: Autoloader:

Manual Loader: Reticle Load and Align:

Field Change:

#### System specifications

Wafer Sizes: XY Stage: Vibration Control: Computer:

Printer: Throughput:

4" 5" 6"

## **Lens Specifications**

Lens Type: Lens Elements: Projection Ratio:

Exposure Spectrum: Chromatic Correction: Alignment Spectrum:

Numerical Aperature: Resolution, Variable NA: Depth of Focus:

Field Size, 1.2um lens:

Field Size, 1.0um lens:

Field Size, 0.8um lens:

Lens Type: Lens Elements:

### **Illumination Specifications**

Automatic Exposure Control:

Lamp Type: Mercury Vapor Control:

Exposure Uniformity

# **Reticle Specifications**

Size (from standard 5"x5" plates): Pellicle Protection:

KLA/NJS Inspectable: Substrate: Alignment Mark:

Size:

Design Flexibility: Generation Technique: Fields per reticle:

**Physical Specifications** 

Footprint:

Dimensions: Service Clearance: Weight:

Facility Requirements: **Ambient Temperature Control:** 

Electrical: Nitrogen or Compressed Air:

Vacuum: Exhaust: Darkfield + - 2 millimeters Darkfield

< 0.13um, 2 sigma

+/- .18 (1.2um), +/-.15um (1.0), +/- .12 (0.8) + / - 50 microns, scanning 200 micron target

Site by Site, electronic

Automatic compensation for environmental fluctuations, image tilt

Site by Site, electronic
Cassette to Cassette, SEMI standard
Input and Output slot, single wafer

Less than 5 minutes

7 seconds

2", 3", 4", 5", 6", 8"

Air bearing, laser metered, resolution of .00004 mm

Air cushioned granite table HP332 or HP362 computer with 3.5" floppy and hard disk (362)

80 column printer, with clean room paper 1.2um 1.0um 0.8um 95wph/16flds 95wph/16flds 85wph/20flds 75wph/24flds 75wph/24flds 60wph/30flds 55wph/35flds 55wph/35flds 45wph/43flds 30wph/61flds 30wph/61flds 25wph/77flds

Catadioptric

5 Total in two groups

Broadband, 390nm-450nm Throughout exposure spectrum

500nm-650nm

variable, .26NA thru .40NA 1.0um standard, 0.8um optional 4.0 ums @ 1.2 um lines for 1.2 um lens 3.0 ums @ 1.0 um lines for 1.0 um lens 2.0 ums @ 0.8 um lines for 0.8 um lens Max area rectangle = 34.2 mm x 13.6 mm Longest rectangle = 39 mm x 11.4 mm Largest square, 18 mm x 18 mm

Max area rectangle = 34.2 mm x 13.6 mm Longest rectangle = 39 mm x 11.4 mm Largest square, 18 mm x 18 mm

Max area rectangle = 31.8 mm x 11.5 mm Longest rectangle = 39 mm x 8.4 mm Largest square, 15.5 mm x 15.5 mm

Catadioptric 5 Total in two groups

Integrated dose monitored for exposure repeatability 200 watt mercury arc, pulsed to 500 watts during exposure

Built in +/- 2.5%

3" x 5" x 0.090" and 5" x 5" x 0.090"

Chrome Side Yes, 4 identical rows Quartz or low expansion Scribe Area

200um square standard, optional crossmask size allows reduction of mark to 70um minimum Verticle or Horizontal alignment marks

E-Beam or optical step and repeat 2 fields standard, up to 7 fields total ( requires optional hardware )

14 feet square

46" width x 50" depth x 78" height Allow 24" on all sides, and in back 3000 lbs

No environmental chamber required 70 degrees , +/- 2 degrees fahrenheit

115 volts, 50/60 Hz, 15 Amps, Inrush current, 35 Amps for 100 milliseconds Minimum 80 psi, 2 CFM, Dry to -40 degrees F dewpoint, filtered to 0.2 microns

One line, minimum 20" Hg, 2 CFM Single exhaust to 3 - 10 CFM at 0.1" H20

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Specifications derived from O.E.M. published documentation, consult manufacturer for updated specification changes.